

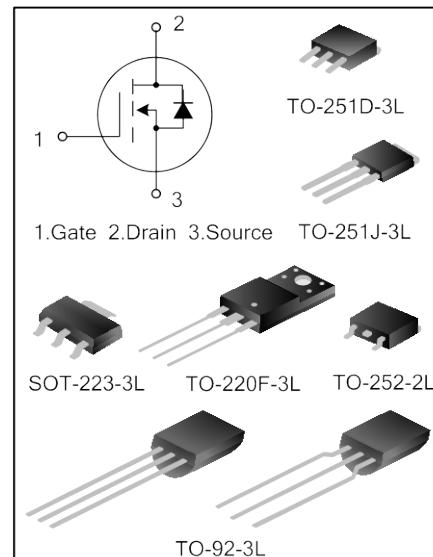


## 1A, 600V N-CHANNEL MOSFET

### GENERAL DESCRIPTION

SVF1N60AM/MJ/B/D/F/H is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary F-Cell™ structure VDMOS technology. The improved planar stripe cell and the improved guard ring terminal have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

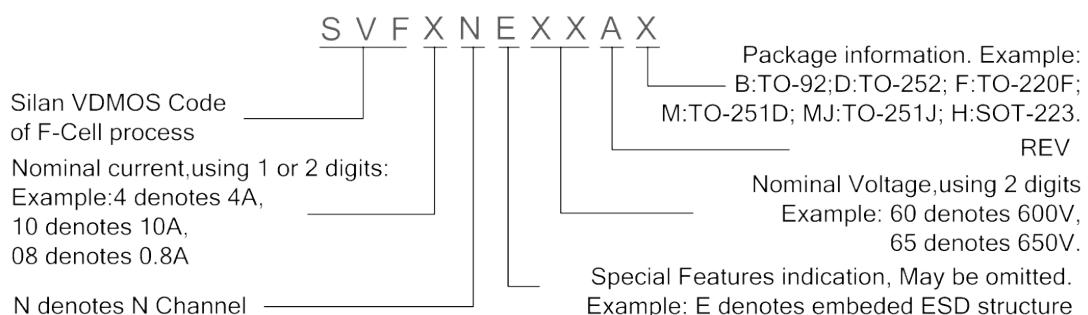
These devices are widely used in AC-DC power suppliers, DC-DC converters and H-bridge PWM motor drivers.



### FEATURES

- \* 1A,600V, $R_{DS(on)}$  (typ.) = $6.8\Omega$ @ $V_{GS}=10V$
- \* Low gate charge
- \* Low Crss
- \* Fast switching
- \* Improved dv/dt capability

### NOMENCLATURE



### ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SVF1N60AM	TO-251D-3L	SVF1N60AM	Pb free	Tube
SVF1N60AMJ	TO-251J-3L	SVF1N60AMJ	Pb free	Tube
SVF1N60ABTR	TO-92-3L	1N60A	Pb free	AMMO
SVF1N60AD	TO-252-2L	SVF1N60AD	Pb free	Tube
SVF1N60ADTR	TO-252-2L	SVF1N60AD	Pb free	Tape & Reel
SVF1N60AF	TO-220F-3L	SVF1N60AF	Pb free	Tube
SVF1N60AH	SOT-223-3L	SVF1N60AH	Pb free	Tape & Reel

ABSOLUTE MAXIMUM RATINGS ( $T_c=25^\circ\text{C}$  unless otherwise noted)

Characteristics	Symbol	Rating					Unit	
		SVF1N 60AM/D	SVF1N 60MJ	SVF1N 60AB	SVF1N 60AF	SVF1N 60AH		
Drain-Source Voltage	$V_{DS}$	600						
Gate-Source Voltage	$V_{GS}$	$\pm 30$						
Drain Current	$I_D$	1.0						
		0.6						
Drain Current Pulsed	$I_{DM}$	4.0						
Power Dissipation( $T_c=25^\circ\text{C}$ ) -Derate above $25^\circ\text{C}$	$P_D$	28	30	9	18	22	W	
		0.22	0.24	0.072	0.14	0.18	W/ $^\circ\text{C}$	
Single Pulsed Avalanche Energy (Note 1)	$E_{AS}$	52						
Operation Junction Temperature Range	$T_J$	$-55 \sim +150$						
Storage Temperature Range	$T_{stg}$	$-55 \sim +150$						

## THERMAL CHARACTERISTICS

Characteristics	Symbol	Rating					Unit
		SVF1N 60AM/D	SVF1N 60MJ	SVF1N 60AB	SVF1N 60AF	SVF1N 60AH	
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	4.55	4.17	13.9	6.94	5.68	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	110	110	120	120	60	$^\circ\text{C/W}$

ELECTRICAL CHARACTERISTICS ( $T_c=25^\circ\text{C}$  unless otherwise noted)

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	$B_{VDSS}$	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	600	--	--	V
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS}=600\text{V}, V_{GS}=0\text{V}$	--	--	1.0	$\mu\text{A}$
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 30\text{V}, V_{DS}=0\text{V}$	--	--	$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\mu\text{A}$	2.0	--	4.0	V
Static Drain- Source On State Resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}, I_D=0.5 \text{ A}$	--	6.8	8.1	$\Omega$
Input Capacitance	$C_{iss}$	$V_{DS}=25\text{V}, V_{GS}=0\text{V}, f=1.0\text{MHz}$	--	139.0	170	$\text{pF}$
Output Capacitance	$C_{oss}$		--	23.4	25	
Reverse Transfer Capacitance	$C_{rss}$		--	0.6	4.5	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=300\text{V}, I_D=1.0\text{A}, R_G=25\Omega$	--	6.1	24	$\text{ns}$
Turn-on Rise Time	$t_r$		--	11.9	52	
Turn-off Delay Time	$t_{d(off)}$		--	8.3	50	
Turn-off Fall Time	$t_f$		--	15.3	64	
Total Gate Charge	$Q_g$	$V_{DS}=480\text{V}, I_D=1.0\text{A}, V_{GS}=10\text{V}$	--	3.37	6.2	$\text{nC}$
Gate-Source Charge	$Q_{gs}$		--	1.16	--	
Gate-Drain Charge	$Q_{gd}$		--	1.04	--	



## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_S$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	1.0	A
Pulsed Source Current	$I_{SM}$		--	--	4.0	
Diode Forward Voltage	$V_{SD}$	$I_S=1.0\text{A}, V_{GS}=0\text{V}$	--	--	1.5	V
Reverse Recovery Time	$T_{rr}$	$I_S=1.0\text{A}, V_{GS}=0\text{V}, dI/dt=100\text{A}/\mu\text{s}$ (Note 2)	--	190	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	0.53	--	$\mu\text{C}$

## Notes:

1.  $L=30\text{mH}, I_{AS}=1.74\text{A}, V_{DD}=110\text{V}, R_G=25\Omega$ , starting  $T_J=25^\circ\text{C}$ ;
2. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$ ;
3. Essentially independent of operating temperature.

## TYPICAL CHARACTERISTICS

Figure 1. On-Region Characteristics

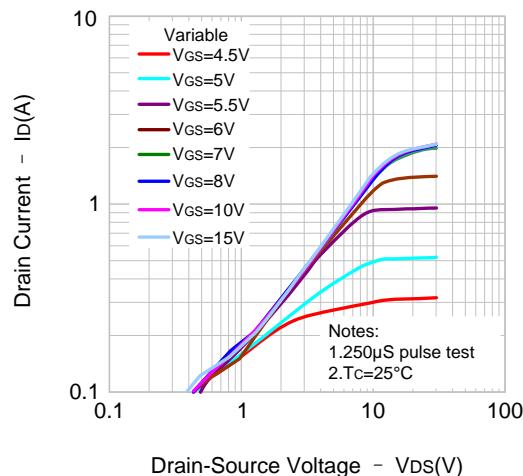


Figure 2. Transfer Characteristics

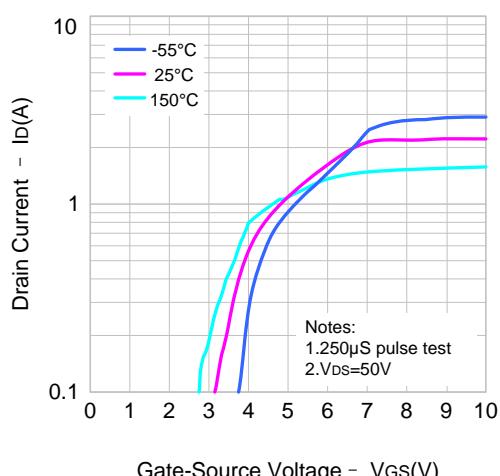


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

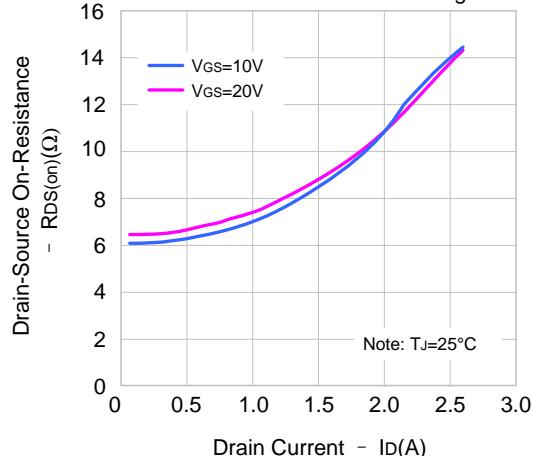
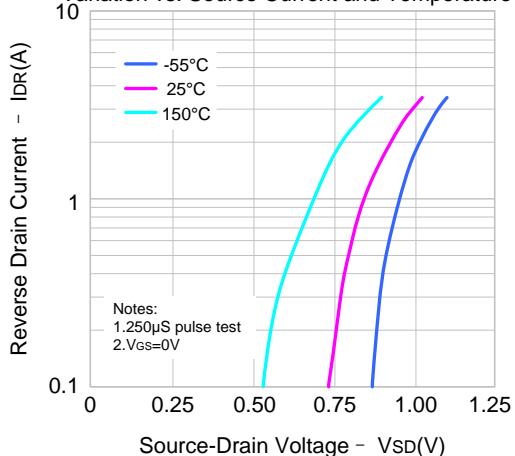
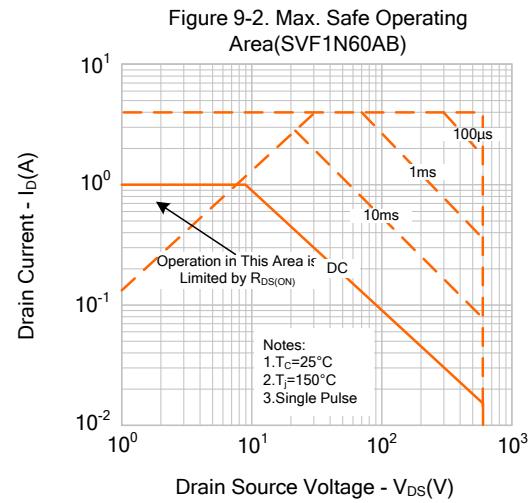
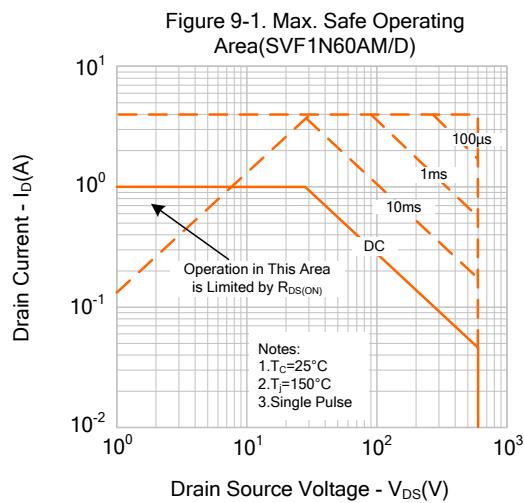
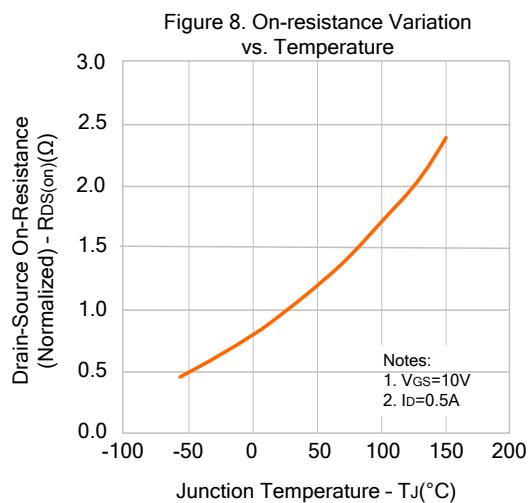
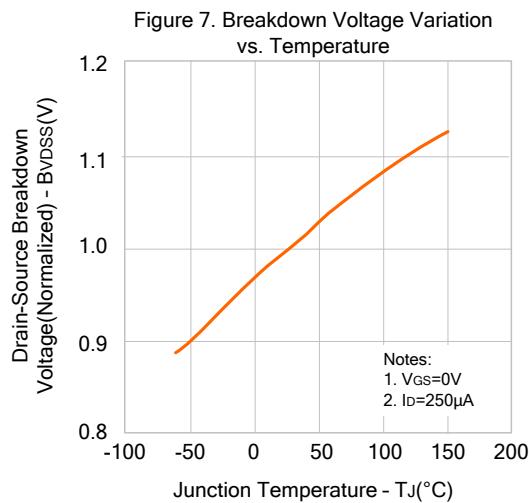
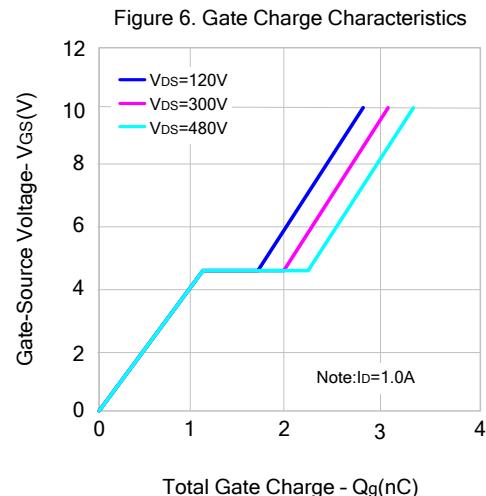
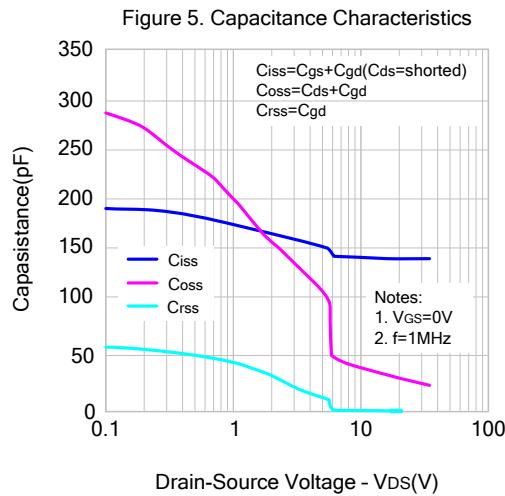


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature





## TYPICAL CHARACTERISTICS (continued)





## TYPICAL CHARACTERISTICS (continued)

Figure 9-3. Max. Safe Operating Area(SVF1N60AF)

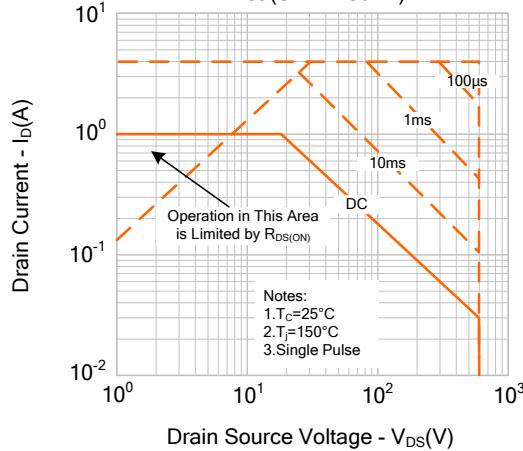


Figure 9-4. Max. Safe Operating Area(SVF1N60AH)

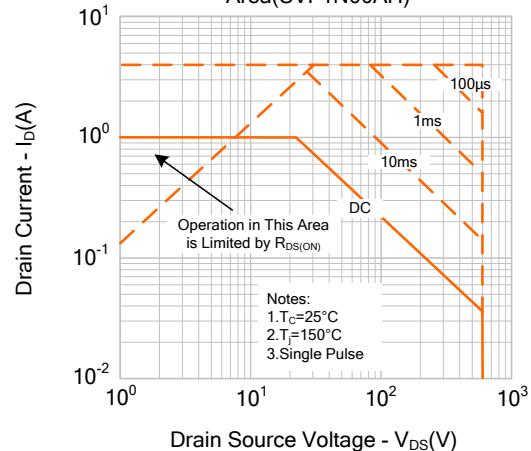


Figure 9-5. Max. Safe Operating Area(SVF1N60AMJ)

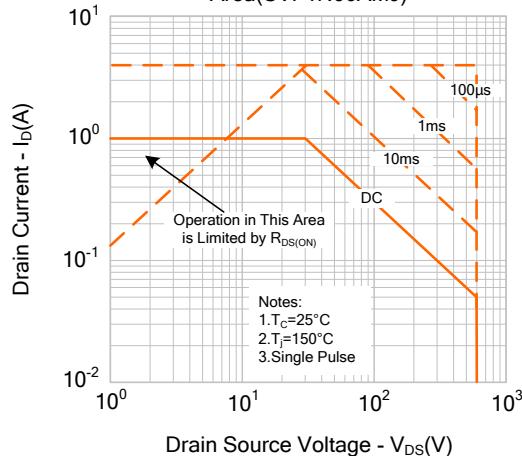
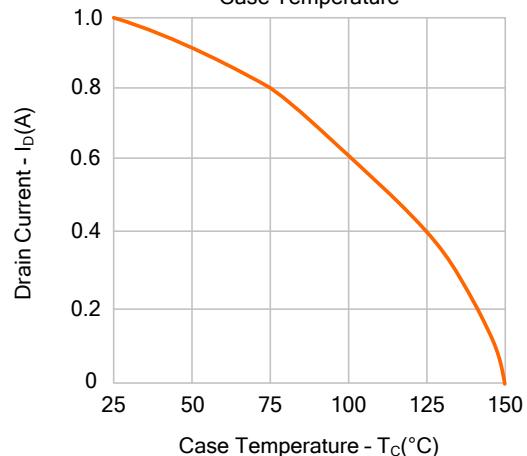


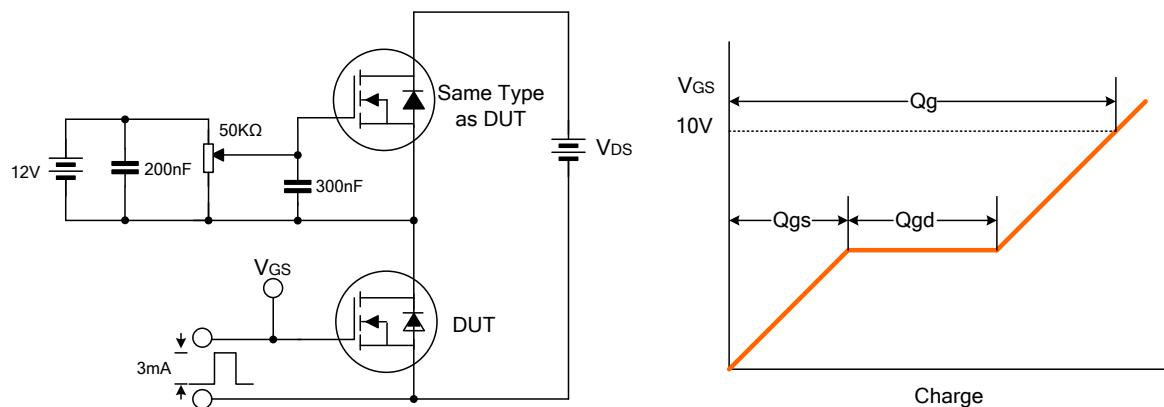
Figure 10. Maximum Drain Current vs. Case Temperature



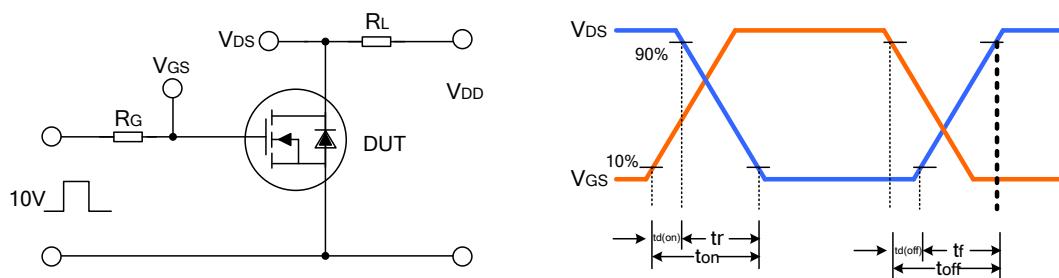


## TYPICAL TEST CIRCUIT

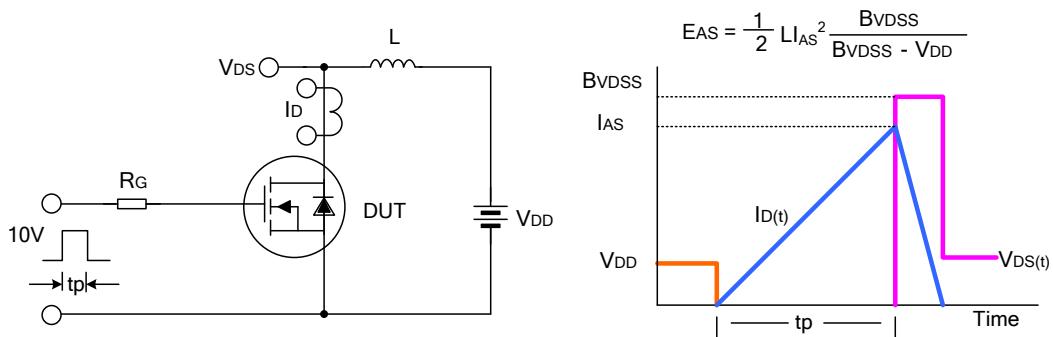
Gate Charge Test Circuit &amp; Waveform



Resistive Switching Test Circuit &amp; Waveform



Unclamped Inductive Switching Test Circuit &amp; Waveform





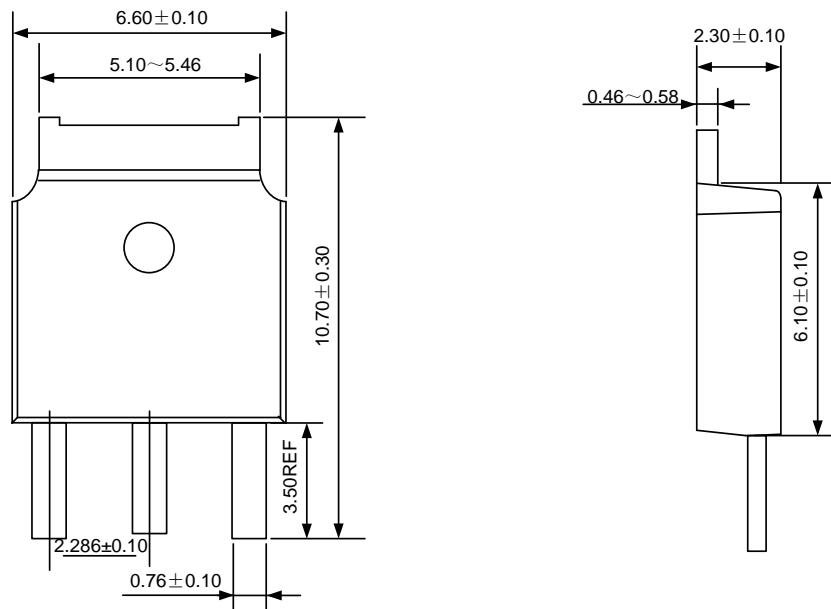
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# SVF1N60AM/MJ/B/D/F/H\_Datasheet

## PACKAGE OUTLINE

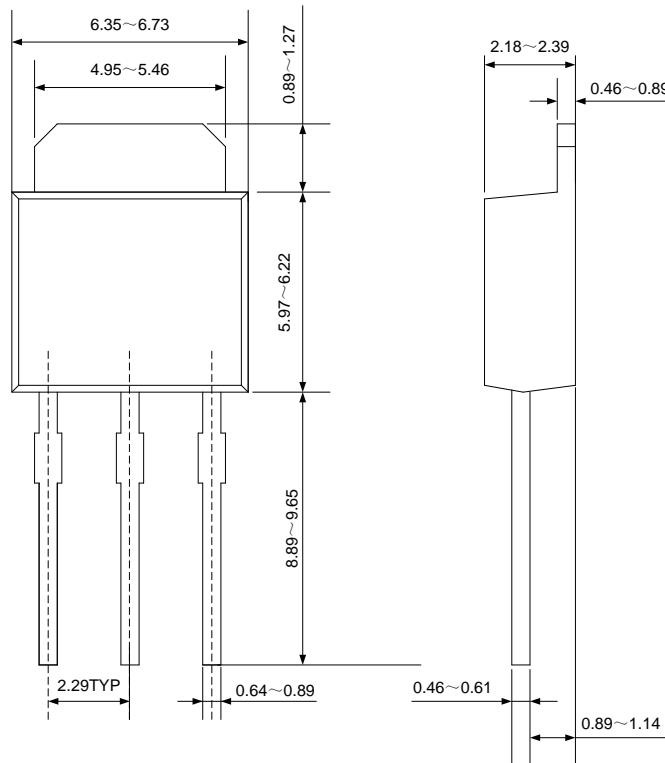
TO-251D-3L

UNIT: mm



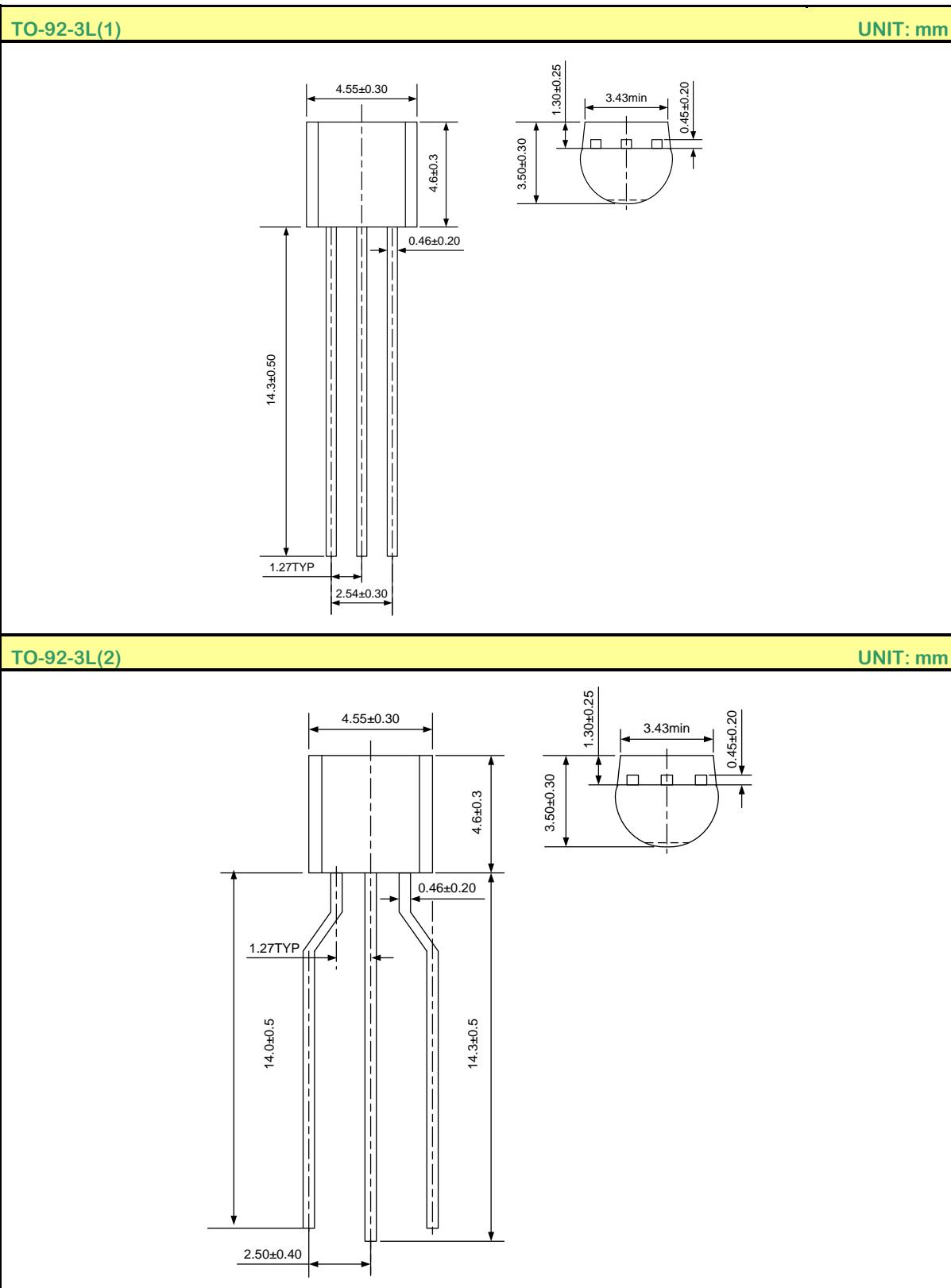
TO-251J-3L

UNIT: mm





**PACKAGE OUTLINE (continued)**

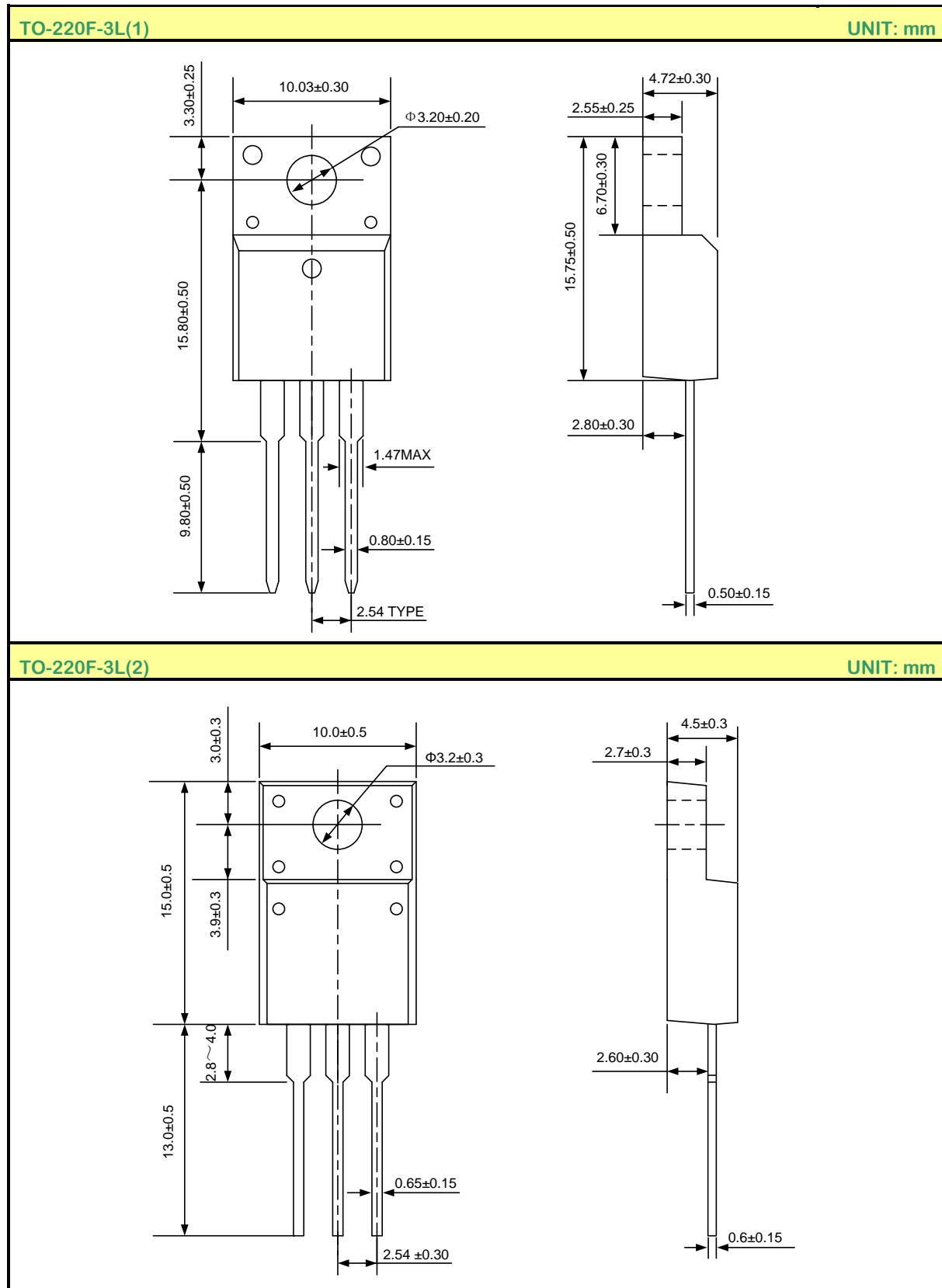




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## SVF1N60AM/MJ/B/D/F/H\_Datasheet

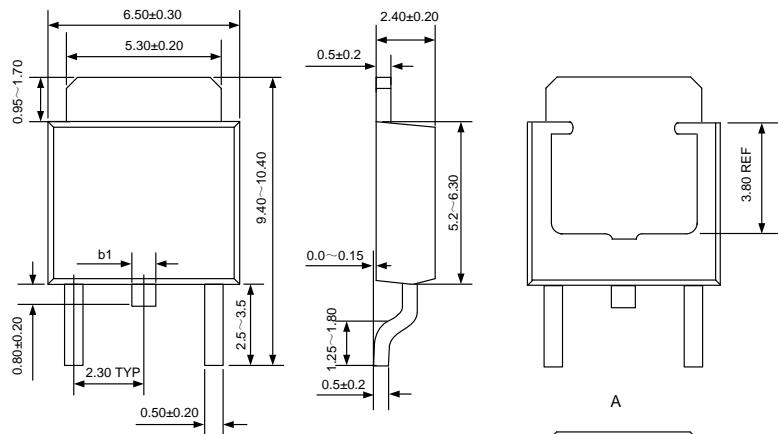
### PACKAGE OUTLINE (continued)



## PACKAGE OUTLINE (continued)

TO-252-2L(1)

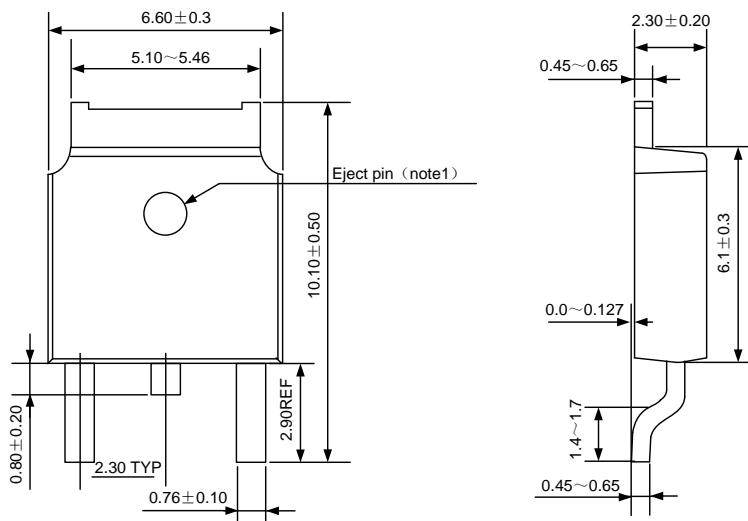
**UNIT: mm**



Note:  
Due to different plastics packaging moulds:  
1.b1 has two values:  $0.80 \pm 0.20$  or  $0.50 \pm 0.20$ ;  
2. There are shape A and B for the heatsink.

TO-252-2L(2)

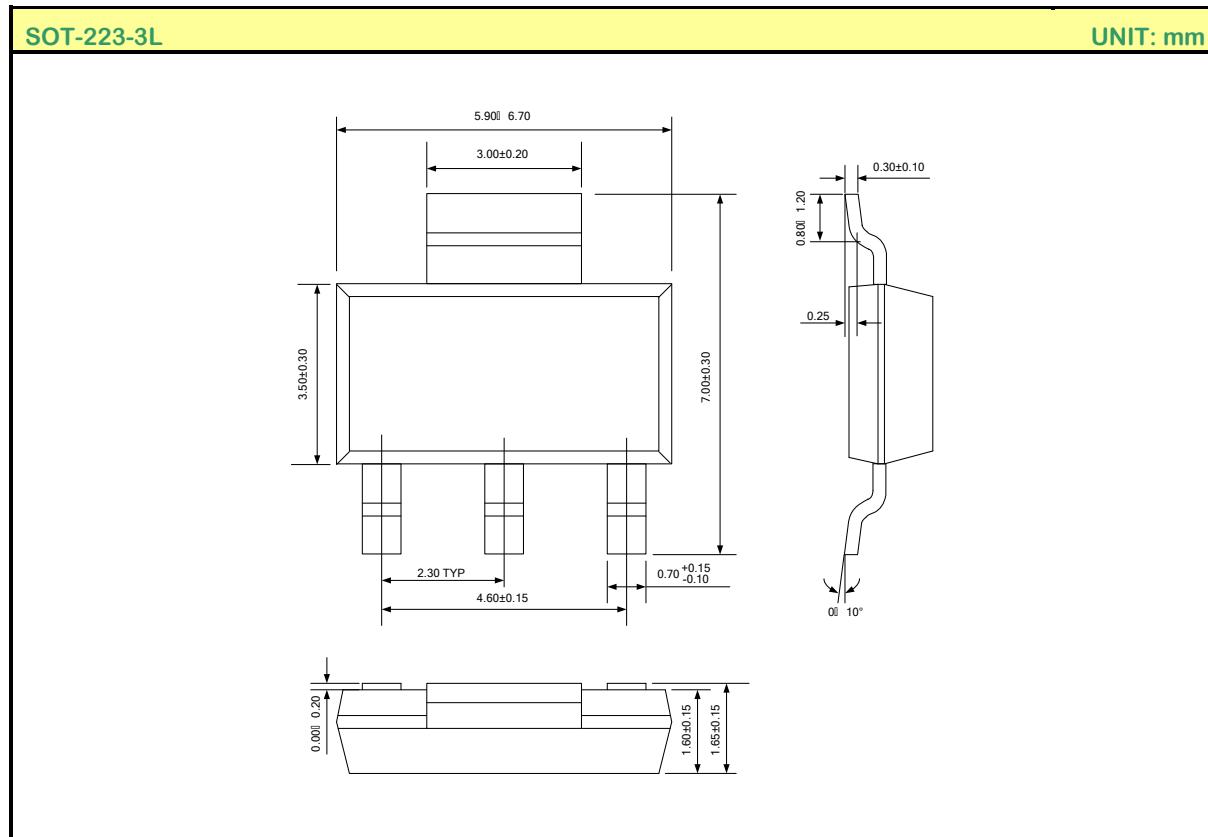
UNIT: mm



**NOTE1 :** There are two conditions for this position:has an eject pin or has no eject pin.



## PACKAGE OUTLINE (continued)



### Disclaimer:

- Silan reserves the right to make changes to the information herein for the improvement of the design and performance without further notice! Customers should obtain the latest relevant information before placing orders and should verify that such information is complete and current.
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- Silan will supply the best possible product for customers!



## ATTACHMENT

### Revision History

Date	REV	Description	Page
2010.09.01	1.0	Original	
2010.10.21	1.1	Modify the template of Datasheet	
2010.11.05	1.2	Modify the part No.; Add SOA and $I_D-T_c$	
2010.11.19	1.3	Omit the Package of TO-220-3L	
2011.01.24	1.4	Modify "Package Outline"	
2011.04.26	1.5	Add the Package of TO-220F-3L	
2011.09.16	1.6	Modify "PACKAGE OUTLINE" ; Add the package of TO-251D-3L	
2011.12.27	1.7	Add the package of SOT-223-3L; Delete the package of TO-251-3L	
2012.03.22	1.8	Add the package of TO-251J-3L	
2012.07.27	1.9	Modify "ELECTRICAL CHARACTERISTICS"	